

20V Dual N-Channel Enhancement Mode MOSFET

VDS= 20V

RDS(ON), Vgs@1.8V, Ids@2A = 50mΩ

RDS(ON), Vgs@2.5V, Ids@5.5A = 32mΩ

RDS(ON), Vgs@4.5V, Ids@6.6A = 24mΩ

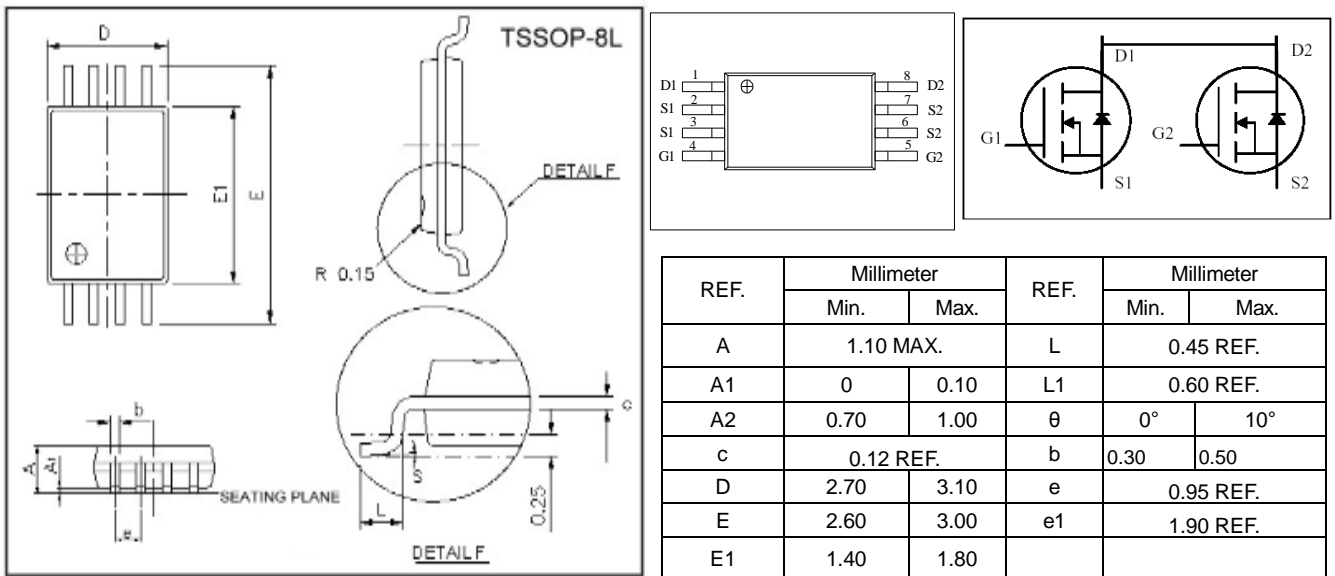
Features

Advanced trench process technology

High Density Cell Design For Ultra Low On-Resistance

Ideal for Li ion battery pack applications

Package Dimensions



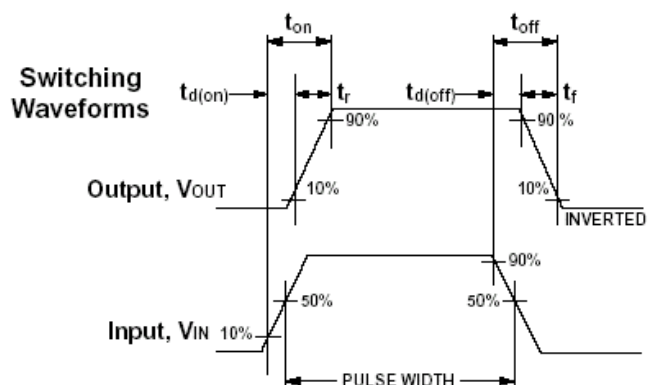
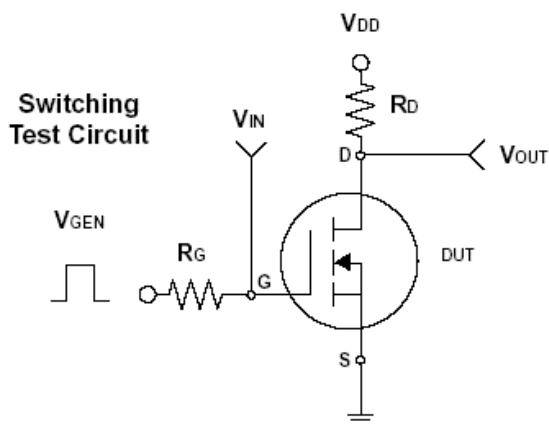
Maximum Ratings and Thermal Characteristics (TA = 25°C unless otherwise noted) 25 °C

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	20	V	
Gate-Source Voltage	V _{GS}	± 12		
Continuous Drain Current	I _D	7	A	
Pulsed Drain Current	I _{DM}	25		
Maximum Power Dissipation	P _D	TA = 25°C	2	W
		TA = 75°C	1.2	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C	
Junction-to-Ambient Thermal Resistance (PCB mounted)	R _{θJA}	62.5	°C/W	

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Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	20			V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 1.8V, I_D = 2A$		36.0	50.0	mΩ
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 2.5V, I_D = 5.5A$		25.0	32.0	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 6.6A$		19.0	24.0	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	0.4		1	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20V, V_{GS} = 0V$			1	μA
Gate Body Leakage	I_{GSS}	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA
Forward Transconductance	g_{fs}	$V_{DS} = 5V, I_D = 7A$		17.7	—	S
Dynamic						
Total Gate Charge	Q_g	$V_{DS} = 10V, I_D = 7A$ $V_{GS} = 4.5V$		8.19	10	nC
Gate-Source Charge	Q_{gs}			1		
Gate-Drain Charge	Q_{gd}			1.93		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 10V,$ $I_D = 1A, V_{GEN} = 4.5V$ $R_G = 6\Omega$		10.87		ns
Turn-On Rise Time	t_r			6.03		
Turn-Off Delay Time	$t_{d(off)}$			28.07		
Turn-Off Fall Time	t_f			4.33		
Input Capacitance	C_{iss}	$V_{DS} = 10V, V_{GS} = 0V$ $f = 1.0\text{ MHz}$		836.88		pF
Output Capacitance	C_{oss}			126.53		
Reverse Transfer Capacitance	C_{rss}			92.78		
Source-Drain Diode						
Max. Diode Forward Current	I_S				2.5	A
Diode Forward Voltage	V_{SD}	$I_S = 1A, V_{GS} = 0V$			1.2	V

Note: Pulse test: pulse width ≤ 300μs, duty cycle ≤ 2%



20V Dual N-Channel Enhancement Mode MOSFET Characteristics Curve

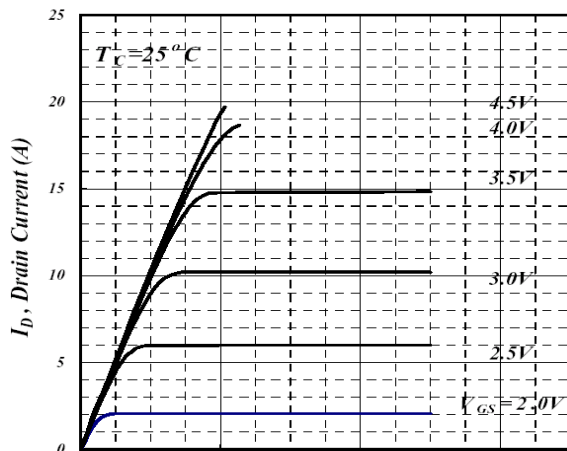


Fig 1. Typical Output Characteristics
 V_{DS} , Drain-to-Source Voltage (V)

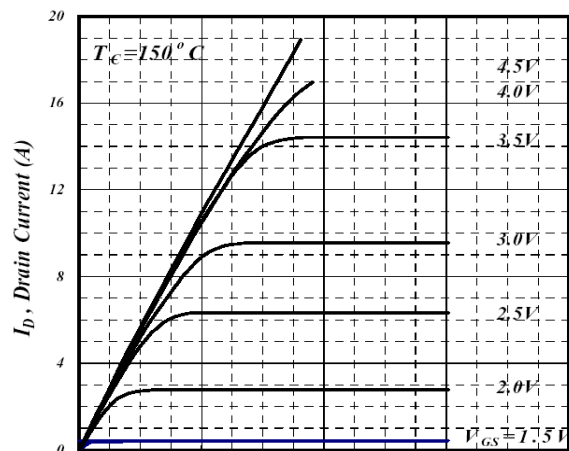


Fig 2. Typical Output Characteristics
 V_{DS} , Drain-to-Source Voltage (V)

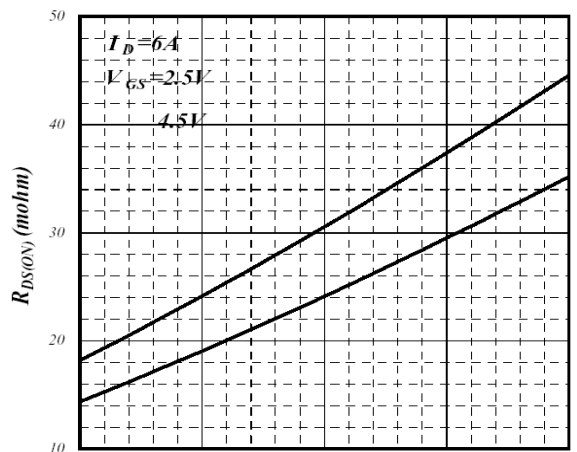


Fig 3. $R_{DS(on)}$ v.s. Junction Temperature
 T_j , Junction Temperature ($^\circ C$)

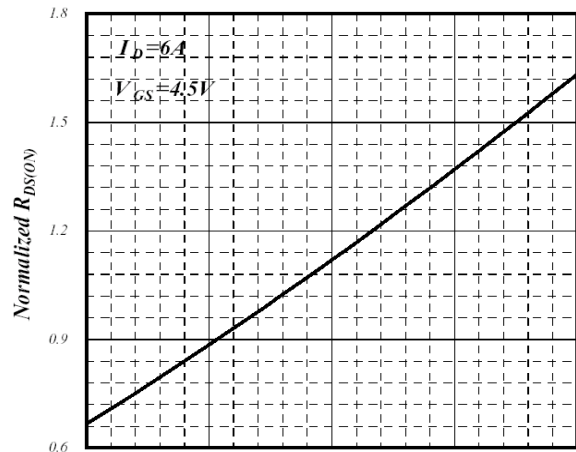


Fig 4. Normalized On-Resistance
 T_j , Junction Temperature ($^\circ C$)
 v.s. Junction Temperature

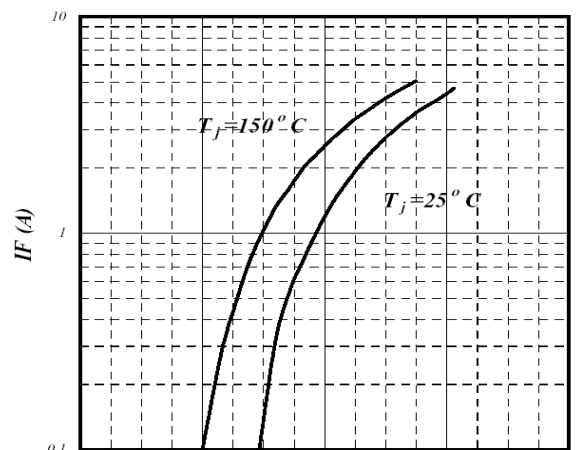


Fig 5. Forward Characteristics of Reverse Diode
 V_{SD} (V)

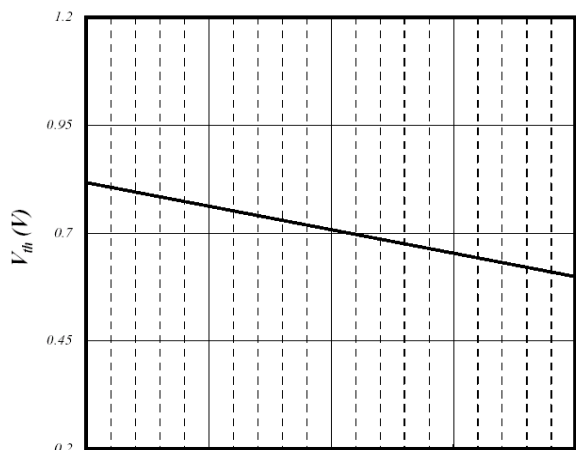


Fig 6. Gate Threshold Voltage v.s. Junction Temperature
 T_j , Junction Temperature ($^\circ C$)